TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

2SK3074

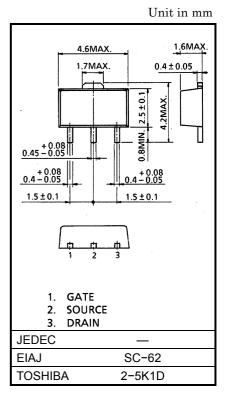
RF POWER MOSFET FOR VHF-AND UHF-BAND POWER AMPLIFIER

•	Output Power	$: P_O \ge 630 \text{ mW}$
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- Power Gain $: GP \ge 14.9 dB$
- Drain Efficiency $\eta_D \ge 45\%$

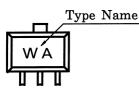
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Drain-Source Voltage	V _{DSS}	30	V	
Gate-Source Voltage	V _{GSS}	25	V	
Drain Current	I _D	1	А	
Drain Power Dissipation	P _D *	3	W	
Channel Temperature	T _{ch}	150	°C	
Storage Temperature Range	T _{stg}	-45~150	°C	



*: Tc = 25°C When mounted on a 1.6mm glass epoxy PCB

MARKING



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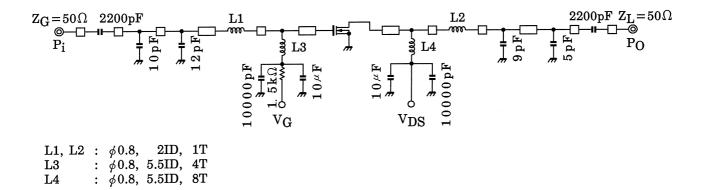
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

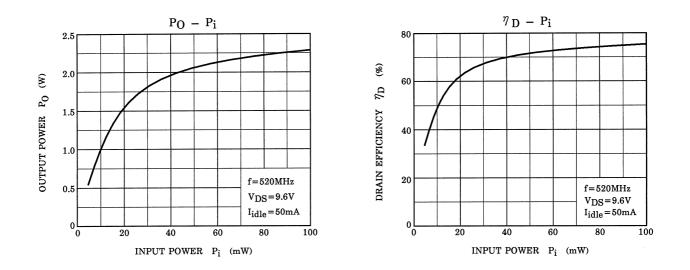
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Power	Po	V _{DS} = 9.6V lidle = 50mA (V _{GS} = adjust) f = 520MHz, P _i = 20mW	630	_	_	mW
Drain Efficiency	η _D		45	_	_	%
Power Gain	GP	$Z_{\rm G} = Z_{\rm L} = 50\Omega$	14.9	_	_	dB
Gate Threshold Voltage	V _{th}	V _{DS} = 9.6V, I _D = 0.5mA	1.4	1.9	2.4	V
Drain Cut-off Current	I _{DSS}	V _{DS} = 20V, V _{GS} = 0	_	—	10	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} = 10V, V _{DS} = 0	_	_	5	μA

HANDLING PRECAUTION

• When handling individual devices, be sure that working desks, human bodies and soldering iron are protected against electrostatic electricity.

RF OUTPUT POWER TEST FIXTURE





CAUTION

These are only typical curves and devices are not necessarily guaranteed at these curves.